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| 3. Nature of conveyance: | |
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| Execution Date: March 14, 2003 | Additional name(s) & address(es) attached? _ Yes _X_ No |
| 4. Application number(s) or patent number(s): | |
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| A. Patent Application No(s). | B. Patent No(s) |
| Filed: | nbers attached? <u>Yes X</u> No |
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| Name: <u>FLESHNER & KIM, LLP</u> | 7. Total fee (37 C.F.R. 3.41) |
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PATENT REEL: 013883 FRAME: 0431

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| b have made a certain new and useful invention, hereby sell, assign and transfer unto YieldBoost Tech, Inc. 6489 Camden Avenue, Suite 101 San Jose, California 95120 muccessors and assigns (hereinafter designated "ASSIGNEE") the entire right, title and interest for ided METHOD OF DETECTING DEFECTS IN TFT-ARRAYS AND A TFT-ARRAY for which an application for United States Letters Patent was filed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for which an application for United States Letters Patent was executed on, and for Which an application for United States Letters Patent was executed on | r the United States of America as defined in 35 U.S.C. 100 in the invent TESTING SYSTEM INCORPORATING THE SAME d identified by United States Serial No; or ; or |
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| I to any improvements, and applications for patent based thereon, growing out of or related to t cessors, assigns and legal representatives, deemed essential to ASSIGNEE's full protection and AND the undersigned hereby grants the firm of FLESHNER & KIM, LLP the power to desirable in order to comply with the rules of any issuing authority, including the United States F | title in and to the invention hereby transferred. b insert on this assignment any further identification that may be neces |
| SNED on the dates indicated aside our signatures: | E SIGNED |
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| Jame: Kyo Young CHUNG | 1/14/2003 |
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PATENT REEL: 013883 FRAME: 0432

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